Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/693,979	NITTA ET AL.	
Examiner	Art Unit	
DANH C. LE	2683	

SEARCHED				
Class	Subclass	Date	Examiner	
455	462	11 16 05	DCL	
	462			
	554.2			
	ļ			
379	428.02			
	428.02			
		1		
		i		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
Interfere	rch	11/7/05	DCL

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor Search (Check for double patent)	11/16/05	XL_
EAST Search		
(USP, USPUB, EPU, JPO, DERWENT)		
Lee Nguyen (455)		
Vuong Hun (455)		
,		
	_	